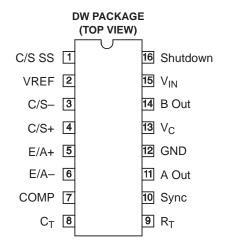
SGLS329-MAY 2006

#### **FEATURES**

- Controlled Baseline
  - One Assembly/Test Site, One Fabrication Site
- Extended Temperature Performance of –55°C to 125°C
- Enhanced Diminishing Manufacturing Sources (DMS) Support
- Enhanced Product-Change Notification
- Qualification Pedigree (1)
- Automatic Feed-Forward Compensation
- Programmable Pulse-by-Pulse Current Limiting
- Automatic Symmetry Correction in Push-Pull Configuration
- Enhanced Load-Response Characteristics
- Parallel Operation Capability for Modular Power Systems
- Differential Current-Sense Amplifier With Wide Common-Mode Range
- Double Pulse Suppression
- 500-mA (Peak) Totem-Pole Outputs
- ±1% Bandgap Reference
- Undervoltage Lockout
- (1) Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.

- Soft-Start Capability
- Shutdown Terminal
- 500-kHz Operation



#### **DESCRIPTION/ORDERING INFORMATION**

The UC1846-EP control IC provides all of the necessary features to implement fixed-frequency, current-mode control schemes, while maintaining a minimum external parts count. The superior performance of this technique can be measured in improved line regulation, enhanced load-response characteristics, and a simpler, easier-to-design control loop. Topological advantages include inherent pulse-by-pulse current-limiting capability, automatic symmetry correction for push-pull converters, and the ability to parallel power modules, while maintaining equal current sharing.

Protection circuitry includes built-in undervoltage lockout and programmable current limit, in addition to soft-start capability. A shutdown function is also available, which can initiate either a complete shutdown with automatic restart or latch the supply off.

Other features include fully latched operation, double pulse suppression, deadline adjust capability, and a  $\pm 1\%$  trimmed bandgap reference.

The UC1846-EP features low outputs in the OFF state.



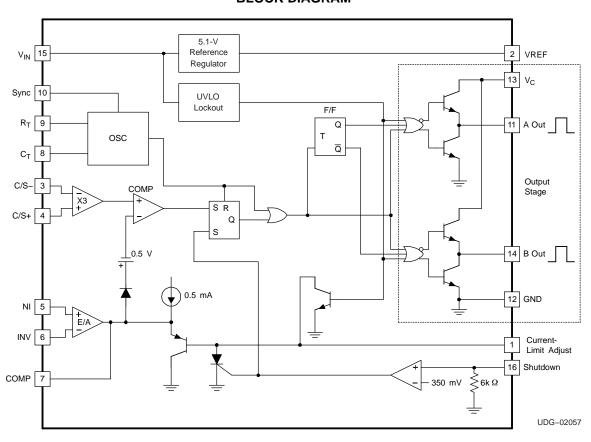
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



#### **ORDERING INFORMATION**

T <sub>A</sub>	PACKAGE	ORDERABLE PART NUMBER	TOP-SIDE MARKING
-55°C to 125°C	SOIC - DW	UC1846MDWREP	UC1846MEP

#### **BLOCK DIAGRAM**





# UC1846-EP CURRENT-MODE PWM CONTROLLER

SGLS329-MAY 2006

# Absolute Maximum Ratings (1)(2)

		MIN	MAX	UNIT
Supply voltage (pin 15)		40	V	
Collector supply voltage (pin 13)			40	V
Output current, source or sink (pins 11, 14)			500	mA
Analog inputs (pins 3, 4, 5, 6, 16)		-0.3	$V_{IN}$	V
Reference output current (pin 2)		-30	mA	
Sync output current (pin 10)		<b>-</b> 5	mA	
Error amplifier output current (pin 7)		-5	mA	
Soft-start sink current (pin 1)		50	mA	
Oscillator charging current (pin 9)		5	mA	
Development of the state of the	T <sub>A</sub> = 25°C		1000	\^/
Power dissipation	$T_C = 25^{\circ}C$			mW
Storage temperature range	-65	150	°C	
Lead temperature (soldering, 10 s)		300	°C	

<sup>(1)</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

<sup>(2)</sup> All voltages are with respect to ground, pin 13. Currents are positive into, negative out of the specified terminal.

# UC1846-EP CURRENT-MODE PWM CONTROLLER

SGLS329-MAY 2006



# **Electrical Characteristics**

 $T_A = -55^{\circ}C$  to 125°C,  $V_{IN} = 15$  V,  $R_T = 10$  k,  $C_T = 4.7$  nF,  $T_A = T_J$  (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Reference		·			
Output voltage	$T_J = 25$ °C, $I_O = 1$ mA	5.05	5.1	5.15	V
Line regulation	V <sub>IN</sub> = 8 V to 40 V		5	20	mV
Load regulation	I <sub>L</sub> = 1 mA to 10 mA		3	15	mV
Temperature stability	Over operating range <sup>(1)</sup>		0.4		mV/°C
Total output variation	Line, load, and temperature <sup>(1)</sup>	5		5.2	V
Output noise voltage	10 Hz $\leq$ f $\leq$ 10 kHz, T <sub>J</sub> = 25°C <sup>(1)</sup>		100		μV
Long-term stability	T <sub>J</sub> = 125°C, 1000 h		5		mV
Short-circuit output current	V <sub>REF</sub> = 0 V	-10	-45		mA
Oscillator		·			
Initial accuracy	T <sub>J</sub> = 25°C	39	43	47	kHz
Voltage stability	V <sub>IN</sub> = 8 V to 40 V		-1	2	%
Temperature stability	Over operating range <sup>(1)</sup>		-1		%
Sync output high level		3.9	4.35		V
Sync output low level			2.3	2.5	V
Sync input high level	Pin 8 = 0 V	3.9			V
Sync input low level	Pin 8 = 0 V			2.5	V
Sync input current	Sync voltage = 3.9 V, Pin 8 = 0 V		1.3	1.5	mA
Error Amplifier		·			
Input offset voltage			0.5	5	mV
Input bias current			-0.6	-1	μΑ
Input offset current			40	250	nA
Common-mode range	V <sub>IN</sub> = 8 V to 40 V	0		V <sub>IN</sub> – 2	V
Open-loop voltage gain	$\Delta V_{O}$ = 1.2 V to 3 V, $V_{CM}$ = 2 V	80	105		dB
Unity gain bandwidth	$T_{J} = 25^{\circ}C^{(1)}$	0.7	1		MHz
CMRR	$V_{CM} = 0 \text{ V to } 38 \text{ V}, V_{IN} = 40 \text{ V}$	75	100		dB
PSRR	V <sub>IN</sub> = 8 V to 40 V	80	105		dB
Output sink current	$V_{ID} = -15 \text{ mV to } -5 \text{ V}, V_{PIN7} = 1.2 \text{ V}$	2	6		mA
Output source current	$V_{ID} = 15 \text{ mV to 5 V}, V_{PIN7} = 2.5 \text{ V}$	-0.4	-0.5		mA
High-level output voltage	$R_L = 15 \text{ k}\Omega \text{ (pin 7)}$	4.3	4.6		V
Low-level output voltage	$R_L = 15 \text{ k}\Omega \text{ (pin 7)}$		0.7	1	V

<sup>(1)</sup> These parameters, although specified over the recommended operating conditions, are not 100% tested in production.



# **Electrical Characteristics (continued)**

 $T_A = -55^{\circ}C$  to 125°C,  $V_{IN} = 15$  V,  $R_T = 10$  k,  $C_T = 4.7$  nF,  $T_A = T_J$  (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Current-Sense Amplifier					
Amplifier gain	V <sub>PIN3</sub> = 0 V, Pin 1 open <sup>(2)(3)</sup>	2.5	2.75	3	V
Maximum differential input signal (V <sub>PIN4</sub> – V <sub>PIN3</sub> )	Pin 1 open, (2) R <sub>L</sub> (pin 7) = 15 kW	1.1	1.2		V
Input offset voltage	V <sub>PIN1</sub> = 0.5 V, Pin 7 open <sup>(2)</sup>		5	25	mV
CMRR	V <sub>CM</sub> = 1 V to 12 V	60	83		dB
PSRR	V <sub>IN</sub> = 8 V to 40 V	60	84		dB
Input bias current	V <sub>PIN1</sub> = 0.5 V, Pin 7 open <sup>(2)</sup>		-2.5	-10	μΑ
Input offset current	V <sub>PIN1</sub> = 0.5 V, Pin 7 open <sup>(2)</sup>		0.08	1	μΑ
Input common-mode range		0		V <sub>IN</sub> – 3	V
Delay to outputs	T <sub>J</sub> = 25°C <sup>(4)</sup>		200	500	ns
Current-Limit Adjust					
Current-limit offset	V <sub>PIN3</sub> = 0 V, V <sub>PIN4</sub> = 0 V, Pin 7 open <sup>(2)</sup>	0.45	0.5	0.55	V
Input bias current	V <sub>PIN5</sub> = V <sub>REF</sub> , V <sub>PIN6</sub> = 0 V		-10	-30	μΑ
Shutdown Terminal		<b>"</b>			
Threshold voltage		250	350	400	mV
Input voltage range		0		$V_{IN}$	V
Minimum latching current (I <sub>PIN1</sub> ) <sup>(5)</sup>		3	1.5		mA
Maximum nonlatching current (I <sub>PIN1</sub> ) <sup>(6)</sup>			1.5	0.8	mA
Delay to outputs	$T_{J} = 25^{\circ}C^{(4)}$		300	600	ns
Output					
Collector-emitter voltage		40			V
Collector leakage current	V <sub>C</sub> = 40 V			200	μΑ
Outrout lave lave	I <sub>SINK</sub> = 20 mA		0.1	0.4	V
Output low level	I <sub>SINK</sub> = 100 mA		0.4	2.1	V
Outrout himbourd	I <sub>SOURCE</sub> = 20 mA	13	13.5		V
Output high level	I <sub>SOURCE</sub> = 100 mA	12	13.5		V
Rise time	$C_L = 1 \text{ nF, } T_J = 25^{\circ}C^{(4)}$		50	300	ns
Fall time	$C_L = 1 \text{ nF, } T_J = 25^{\circ}C^{(4)}$		50	300	ns
Undervoltage Lockout		,		1	
Start-up threshold			7.7	8	V
Threshold hysteresis			0.75		V
Total Standby Current	<u> </u>	1		l	
Supply current			17	21	mA

- (2) Parameter measured at trip point of latch with  $V_{PIN5} = V_{REF}$ ,  $V_{PIN6} = 0$  V. (3) Amplifier gain defined as:

$$G = \frac{\left(\Delta V_{PIN7}\right)}{\left(\Delta V_{PIN4}\right)}$$

- where  $V_{\text{PIN4}} = 0$  to 1 V These parameters, although specified over the recommended operating conditions, are not 100% tested in production.
- Current into pin 1 is ensured to latch circuit in shutdown state.
- (6) Current into pin 1 is ensured not to latch circuit in shutdown state.



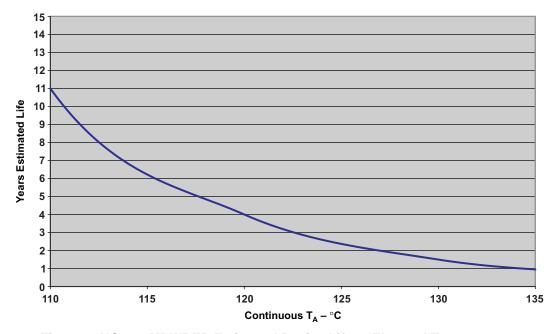
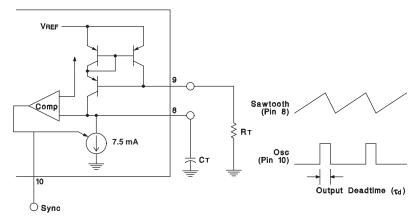


Figure 1. UC1846MDWREP Estimated Device Life at Elevated Temperatures Wirebond Voiding Fail Modes



#### **APPLICATION INFORMATION**



Output deadtime is determined by the external capacitor,  $C_T$ , according to the formula:

$$\label{eq:total_$$

Figure 2. Oscillator Circuit

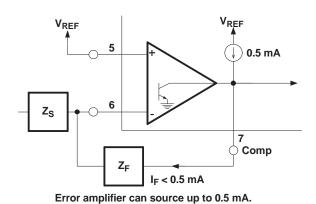


Figure 3. Error-Amplifier Output Configuration

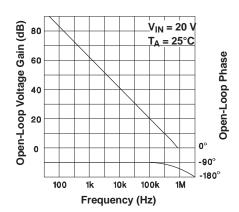


Figure 4. Error-Amplifier Gain and Phase vs Frequency



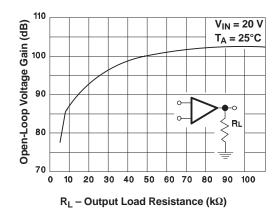
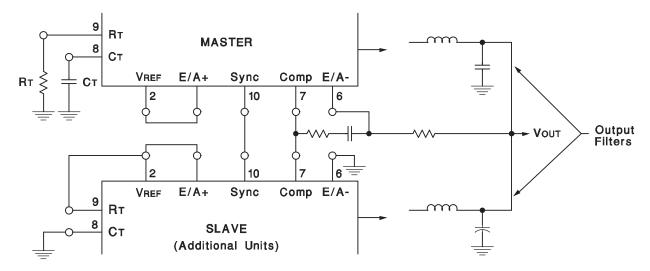


Figure 5. Error-Amplifier Open-Logic DC Gain vs Load Resistance



Slaving allows parallel operation of two or more units with equal current sharing.

Figure 6. Parallel Operation



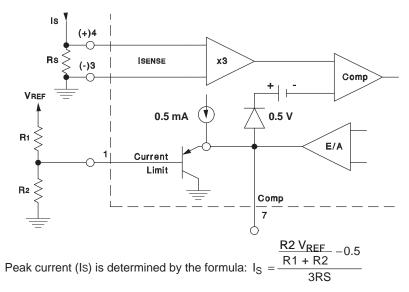


Figure 7. Pulse-by-Pulse Current Limiting



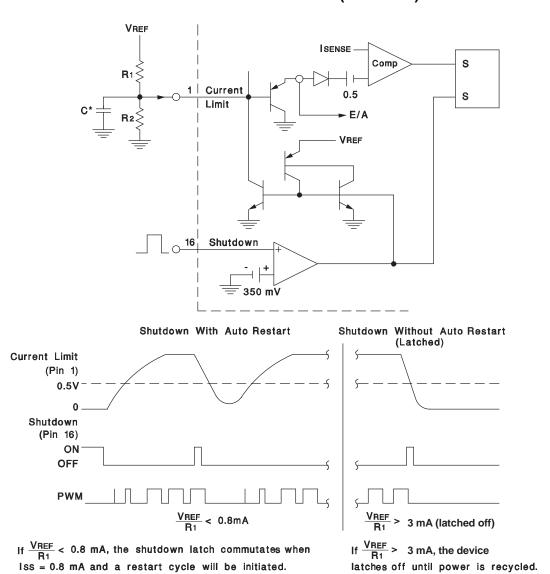
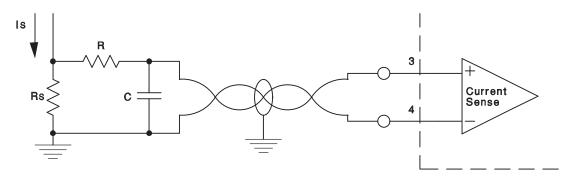


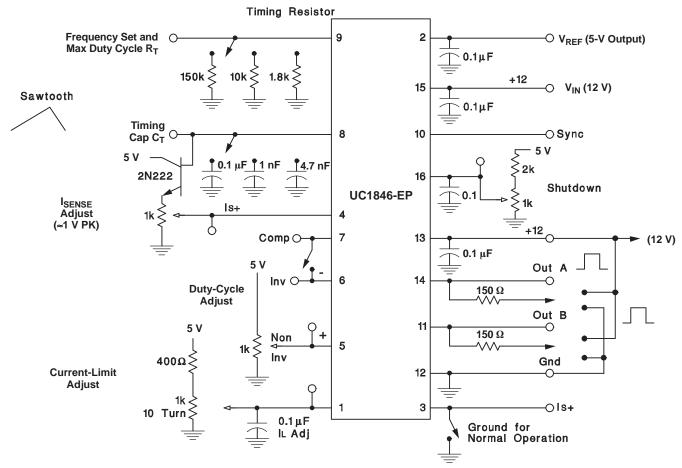
Figure 8. Soft-Start and Shutdown/Restart Functions



A small RC filter may be required in some applications to reduce switch transients. Differential input allows remote noise-free sensing.

Figure 9. Current-Sense Amplifier Connection





<sup>-</sup>Bypass capacitance should be low ESR and ESL type.

Figure 10. Open-Loop Test Circuit

<sup>-</sup>Short pins 6 and 7 for unity gain testing.



# PACKAGE OPTION ADDENDUM

10-Dec-2020

#### PACKAGING INFORMATION

www.ti.com

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
UC1846MDWREP	ACTIVE	SOIC	DW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	UC1846MEP	Samples
V62/06606-01XE	ACTIVE	SOIC	DW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	UC1846MEP	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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# **PACKAGE OPTION ADDENDUM**

10-Dec-2020

#### OTHER QUALIFIED VERSIONS OF UC1846-EP:

• Space: UC1846-SP

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Space Radiation tolerant, ceramic packaging and qualified for use in Space-based application

7.5 x 10.3, 1.27 mm pitch

SMALL OUTLINE INTEGRATED CIRCUIT

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





SOIC



#### NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing
- per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm, per side.
- 5. Reference JEDEC registration MS-013.



SOIC



#### NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



#### NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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